## Notice of References Cited Application/Control No. | Applicant(s)/Patent Under | Reexamination | TANAKA ET AL. | Examiner | Art Unit | Chuc D Tran | 2821 | Page 1 of 1

## U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	Α	US-6,433,756	08-2002	Sievenpiper et al.	343/909
	В	US-6,545,647	04-2003	Sievenpiper et al.	343/795
	ပ	US-6,262,495	07-2001	Yablonovitch et al.	307/101
	D	US-6,483,481	11-2002	Sievenpiper et al.	343/909
	E	US-6,262,495	07-2001	Yablonovitch et al.	307/101
	F	US-6,366,254	04-2002	Sievenpiper et al.	343/770
	G	US-5,831,557	11-1998	Handley, Maynard J.	341/67
	Н	US-			
	1	US-			-
	J	US-			
	К	US-			
	L	US-			
	М	US-			

## **FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	0					
	Р					·
	σ					
	R				·	
	S					
	Т					

## **NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)		
	U			
	٧			
	W.			
	х			

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.